

Silicon Carbide Junction Transistor/Schottky Diode Co-pack

| | | |
|---------------------------------------|---|---------------|
| V_{DS} | = | 1200 V |
| $R_{DS(ON)}$ | = | 120 mΩ |
| I_D ($T_C = 25^\circ\text{C}$) | = | 25 A |
| h_{FE} ($T_C = 25^\circ\text{C}$) | | 100 |

Features

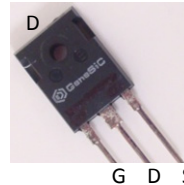
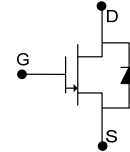
- 175°C Maximum Operating Temperature
- Gate Oxide free SiC switch
- Exceptional Safe Operating Area
- Integrated SiC Schottky Rectifier
- Excellent Gain Linearity
- Temperature Independent Switching Performance
- Low output capacitance
- Positive temperature co-efficient of $R_{DS,ON}$
- Suitable for connecting an anti-parallel diode

Advantages

- Compatible with Si MOSFET/IGBT Gate Drive ICs
- > 20 μs Short-Circuit Withstand Capability
- Lowest-in-class Conduction Losses
- High Circuit Efficiency
- Minimal Input Signal distortion
- High Amplifier Bandwidth
- Reduced cooling requirements
- Reduced system size

Package

- RoHS Compliant


TO-247AB


Applications

- Down Hole Oil Drilling, Geothermal Instrumentation
- Hybrid Electric Vehicles (HEV)
- Solar Inverters
- Switched-Mode Power Supply (SMPS)
- Power Factor Correction (PFC)
- Induction Heating
- Uninterruptible Power Supply (UPS)
- Motor Drives

Maximum Ratings at $T_j = 175^\circ\text{C}$, unless otherwise specified

| Parameter | Symbol | Conditions | Values | Unit |
|-----------------------------------|-----------|---|---|------|
| SiC Junction Transistor | | | | |
| Drain – Source Voltage | V_{DS} | $V_{GS} = 0\text{ V}$ | 1200 | V |
| Continuous Drain Current | I_D | $T_{C,MAX} = 95^\circ\text{C}$ | 10 | A |
| Gate Peak Current | I_{GM} | | 10 | A |
| Turn-Off Safe Operating Area | RBSOA | $T_{VJ} = 175^\circ\text{C}$, $I_G = 1\text{ A}$, Clamped Inductive Load | $I_{D,max} = 10$ @ $V_{DS} \leq V_{DSmax}$ | A |
| Short Circuit Safe Operating Area | SCSOA | $T_{VJ} = 175^\circ\text{C}$, $I_G = 1\text{ A}$, $V_{DS} = 800\text{ V}$, Non Repetitive | 20 | μs |
| Reverse Gate – Source Voltage | V_{SG} | | 30 | V |
| Reverse Drain – Source Voltage | V_{SD} | | 25 | V |
| Power Dissipation | P_{tot} | $T_C = 95^\circ\text{C}$ | 91 | W |
| Storage Temperature | T_{stg} | | -55 to 175 | °C |

Free-wheeling Silicon Carbide diode

| | | | | |
|--------------------------------------|------------|--|-----|---|
| DC-Forward Current | I_F | $T_C \leq 150^\circ\text{C}$ | 10 | A |
| Non Repetitive Peak Forward Current | I_{FM} | $T_C = 25^\circ\text{C}$, $t_P = 10\ \mu\text{s}$ | 280 | A |
| Surge Non Repetitive Forward Current | $I_{F,SM}$ | $t_P = 10\text{ ms}$, half sine, $T_C = 25^\circ\text{C}$ | 65 | A |

Thermal Characteristics

| | | | | |
|-------------------------------------|------------|-------------------------|------|------|
| Thermal resistance, junction - case | R_{thJC} | SiC Junction Transistor | 0.88 | °C/W |
| Thermal resistance, junction - case | R_{thJC} | SiC Diode | 0.85 | °C/W |

Mechanical Properties

| | | | | |
|-----------------|---|--|-----|----|
| Mounting torque | M | | 0.6 | Nm |
|-----------------|---|--|-----|----|

Electrical Characteristics at $T_j = 175\text{ }^\circ\text{C}$, unless otherwise specified

| Parameter | Symbol | Conditions | Values | | | Unit | |
|---|-------------------|---|--|------|------|---------------|----|
| | | | min. | typ. | max. | | |
| SJT On-State Characteristics | | | | | | | |
| Drain – Source On Resistance | $R_{DS(ON)}$ | $I_D = 10\text{ A}, I_G = 200\text{ mA}, T_j = 25\text{ }^\circ\text{C}$ | | 120 | | m Ω | |
| | | $I_D = 10\text{ A}, I_G = 400\text{ mA}, T_j = 125\text{ }^\circ\text{C}$ | | 150 | | | |
| | | $I_D = 10\text{ A}, I_G = 800\text{ mA}, T_j = 175\text{ }^\circ\text{C}$ | | 220 | | | |
| Gate Forward Voltage | $V_{GS(FWD)}$ | $I_G = 500\text{ mA}, T_j = 25\text{ }^\circ\text{C}$ | | 3.3 | | V | |
| | | $I_G = 500\text{ mA}, T_j = 175\text{ }^\circ\text{C}$ | | 3.1 | | | |
| DC Current Gain | h_{FE} | $V_{DS} = 5\text{ V}, I_D = 10\text{ A}, T_j = 25\text{ }^\circ\text{C}$ | | 100 | | | |
| | | $V_{DS} = 5\text{ V}, I_D = 10\text{ A}, T_j = 175\text{ }^\circ\text{C}$ | | TBD | | | |
| SJT Off-State Characteristics | | | | | | | |
| Drain Leakage Current | I_{DSS} | $V_R = 1200\text{ V}, V_{GS} = 0\text{ V}, T_j = 25\text{ }^\circ\text{C}$ | | 350 | | nA | |
| | | $V_R = 1200\text{ V}, V_{GS} = 0\text{ V}, T_j = 125\text{ }^\circ\text{C}$ | | 530 | | | |
| | | $V_R = 1200\text{ V}, V_{GS} = 0\text{ V}, T_j = 175\text{ }^\circ\text{C}$ | | 700 | | | |
| Gate Leakage Current | I_{SG} | $V_{SG} = 20\text{ V}, T_j = 25\text{ }^\circ\text{C}$ | | 20 | | nA | |
| SJT Capacitance Characteristics | | | | | | | |
| Input Capacitance | C_{ISS} | $V_{GS} = 0\text{ V}, V_D = 1\text{ V}, f = 1\text{ MHz}$ | | tbd | | pF | |
| Reverse Transfer/Output Capacitance | C_{rss}/C_{oss} | $V_D = 1\text{ V}, f = 1\text{ MHz}$ | | tbd | | pF | |
| SJT Switching Characteristics | | | | | | | |
| Turn On Delay Time | $t_{d(on)}$ | $V_{DD} = 800\text{ V}, I_D = 10\text{ A},$ $R_{G(on)} = R_{G(off)} = \text{tbd } \Omega,$ FWD = GB10SLT12, $T_j = 25\text{ }^\circ\text{C}$ Refer to Figure 15 for gate current waveform | | tbd | | ns | |
| Rise Time | t_r | | | tbd | | ns | |
| Turn Off Delay Time | $t_{d(off)}$ | | | tbd | | ns | |
| Fall Time | t_f | | | tbd | | ns | |
| Turn-On Energy Per Pulse | E_{on} | | | tbd | | μJ | |
| Turn-Off Energy Per Pulse | E_{off} | | | tbd | | μJ | |
| Total Switching Energy | E_{ts} | | | tbd | | μJ | |
| Turn On Delay Time | $t_{d(on)}$ | | $V_{DD} = 800\text{ V}, I_D = 10\text{ A},$ $R_{G(on)} = R_{G(off)} = \text{tbd } \Omega,$ FWD = GB10SLT12, $T_j = 175\text{ }^\circ\text{C}$ Refer to Figure 15 for gate current waveform | | tbd | | ns |
| Rise Time | t_r | | | | tbd | | ns |
| Turn Off Delay Time | $t_{d(off)}$ | | | | tbd | | ns |
| Fall Time | t_f | | | tbd | | ns | |
| Turn-On Energy Per Pulse | E_{on} | | | tbd | | μJ | |
| Turn-Off Energy Per Pulse | E_{off} | | | tbd | | μJ | |
| Total Switching Energy | E_{ts} | | | tbd | | μJ | |
| Free-wheeling Silicon Carbide Schottky Diode | | | | | | | |
| Forward Voltage | V_F | $I_F = 10\text{ A}, V_{GE} = 0\text{ V},$ $T_j = 25\text{ }^\circ\text{C} (175\text{ }^\circ\text{C})$ | | 1.55 | | V | |
| Diode Knee Voltage | $V_{D(knee)}$ | $T_j = 25\text{ }^\circ\text{C}, I_F = 1\text{ mA}$ | | 0.8 | | V | |
| Peak Reverse Recovery Current | I_{rrm} | $I_F = 10\text{ A}, V_{GE} = 0\text{ V}, V_R = 800\text{ V},$ $-di_F/dt = 625\text{ A}/\mu\text{s}, T_j = 175\text{ }^\circ\text{C}$ | | tbd | | A | |
| Reverse Recovery Time | t_{rr} | | | tbd | | ns | |
| Rise Time | t_r | $V_{DD} = 800\text{ V}, I_D = 10\text{ A},$ $R_{gon} = R_{goff} = \text{tbd } \Omega,$ $T_j = 25\text{ }^\circ\text{C}$ | | tbd | | ns | |
| Fall Time | t_f | | | tbd | | ns | |
| Turn-On Energy Loss Per Pulse | E_{on} | | | tbd | | μJ | |
| Turn-Off Energy Loss Per Pulse | E_{off} | | | tbd | | μJ | |
| Reverse Recovery Charge | Q_{rr} | | | tbd | | nC | |
| Rise Time | t_r | $V_{DD} = 800\text{ V}, I_D = 10\text{ A},$ $R_{gon} = R_{goff} = \text{tbd } \Omega,$ $T_j = 175\text{ }^\circ\text{C}$ | | tbd | | ns | |
| Fall Time | t_f | | | tbd | | ns | |
| Turn-On Energy Loss Per Pulse | E_{on} | | | tbd | | μJ | |
| Turn-Off Energy Loss Per Pulse | E_{off} | | | tbd | | μJ | |
| Reverse Recovery Charge | Q_{rr} | | | tbd | | nC | |

Figures

TBD

TBD

Figure 1: Typical Output Characteristics at 25 °C

Figure 2: Typical Output Characteristics at 125 °C

TBD

TBD

Figure 3: Typical Output Characteristics at 175 °C

Figure 4: Typical Gate Source I-V Characteristics vs. Temperature

TBD

TBD

Figure 5: Normalized On-Resistance and Current Gain vs. Temperature

Figure 6: Typical Blocking Characteristics

TBD

Figure 7: Capacitance Characteristics

TBD

Figure 8: Capacitance Characteristics

TBD

Figure 9: Typical Hard-switched Turn On Waveforms

TBD

Figure 10: Typical Hard-switched Turn Off Waveforms

TBD

Figure 11: Typical Turn On Energy Losses and Switching Times vs. Temperature

TBD

Figure 12: Typical Turn Off Energy Losses and Switching Times vs. Temperature

TBD

Figure 13: Typical Turn On Energy Losses vs. Drain Current

TBD

Figure 14: Typical Turn Off Energy Losses vs. Drain Current

TBD

Figure 15: Typical Gate Current Waveform

TBD

Figure 16: Typical Hard Switched Device Power Loss vs. Switching Frequency¹

TBD

Figure 17: Power Derating Curve

¹ – Representative values based on device switching energy loss. Actual losses will depend on gate drive conditions, device load, and circuit topology.

Figure 18: Forward Bias Safe Operating Area

TBD

TBD

Figure 19: Turn-Off Safe Operating Area

Figure 20: Transient Thermal Impedance

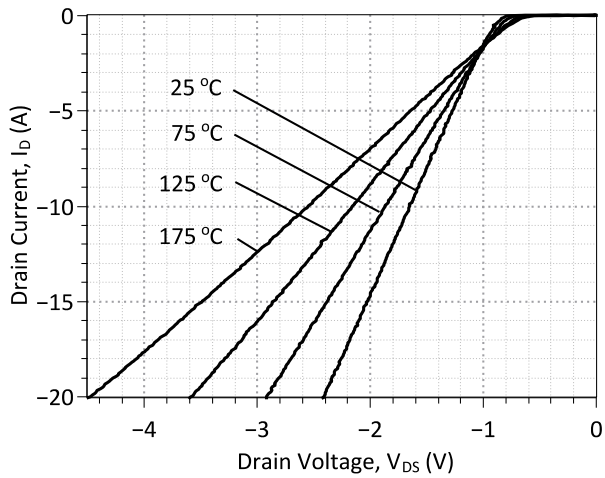


Figure 21: Typical FWD Forward Characteristics

Gate Drive Theory of Operation for the GA10SICP12-263

The SJT transistor is a current controlled transistor which requires a positive gate current for turn-on as well as to remain in on-state. An ideal gate current waveform for ultra-fast switching of the SJT, while maintaining low gate drive losses, is shown in Figure 22.

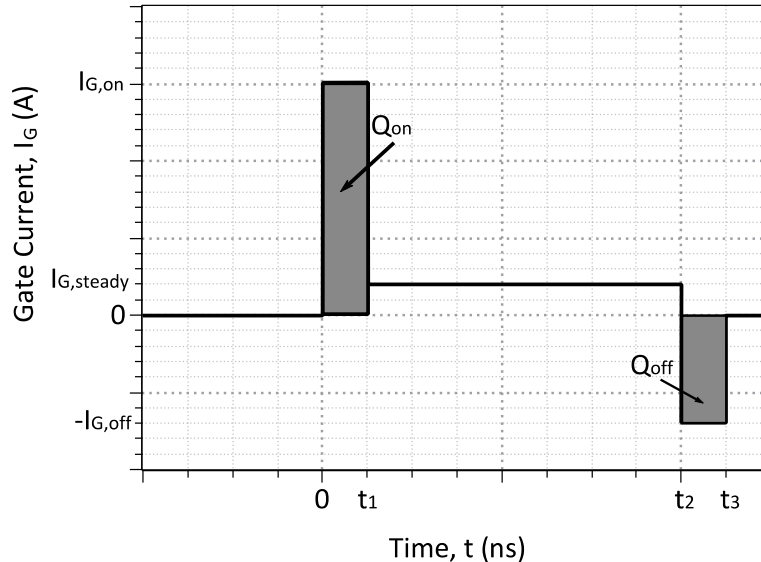


Figure 22: Idealized Gate Current Waveform

Gate Currents, $I_{G,pk}/-I_{G,pk}$ and Voltages during Turn-On and Turn-Off

An SJT is rapidly switched from its blocking state to on-state, when the necessary gate charge, Q_G , for turn-on is supplied by a burst of high gate current, $I_{G,on}$, until the gate-source capacitance, C_{GS} , and gate-drain capacitance, C_{GD} , are fully charged.

$$I_{G,on} * t_1 \geq Q_{gs} + Q_{gd}$$

The $I_{G,on}$ pulse should ideally terminate, when the drain voltage falls to its on-state value, in order to avoid unnecessary drive losses during the steady on-state. In practice, the rise time of the $I_{G,on}$ pulse is affected by the parasitic inductances, L_{par} in the module and drive circuit. A voltage developed across the parasitic inductance in the source path, L_s , can de-bias the gate-source junction, when high drain currents begin to flow through the device. The applied gate voltage should be maintained high enough, above the $V_{GS,ON}$ level to counter these effects.

A high negative peak current, $-I_{G,off}$ is recommended at the start of the turn-off transition, in order to rapidly sweep out the injected carriers from the gate, and achieve rapid turn-off. While satisfactory turn off can be achieved with $V_{GS} = 0$ V, a negative gate voltage V_{GS} may be used in order to speed up the turn-off transition.

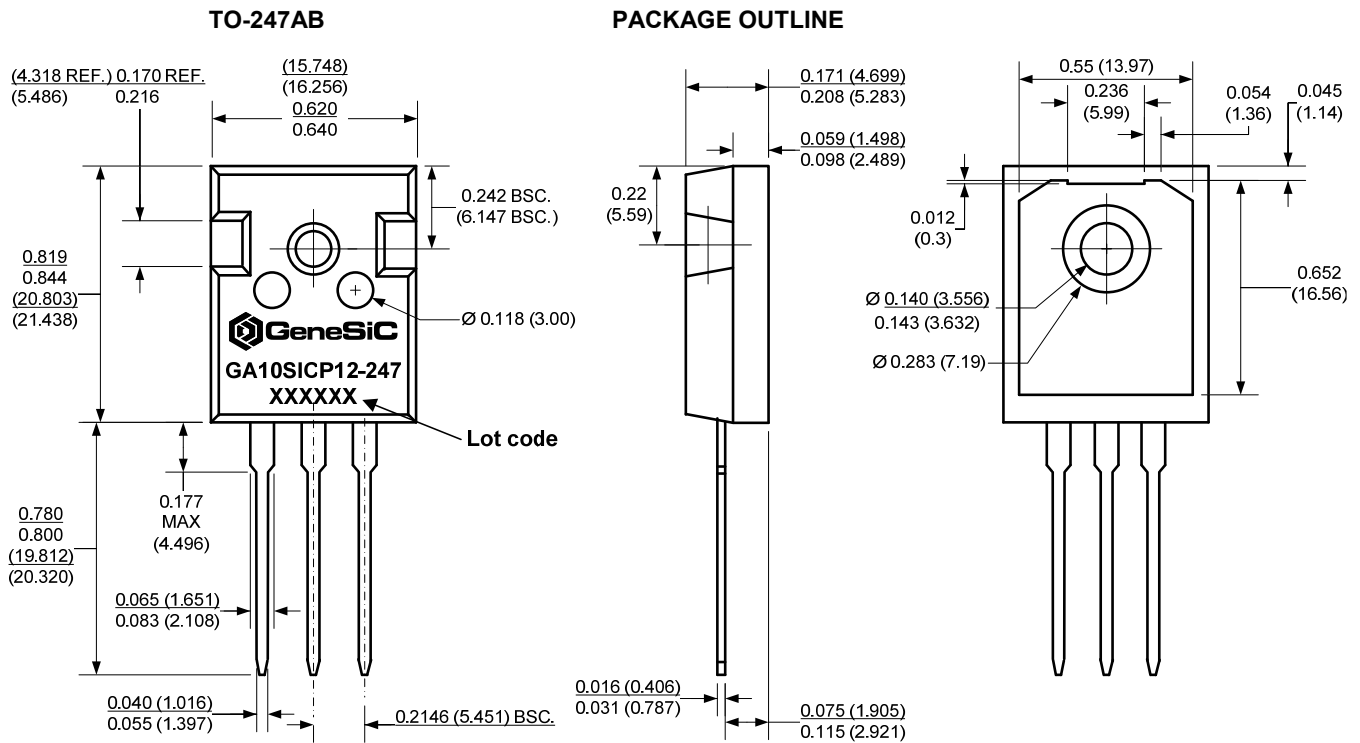
Steady On-State

After the device is turned on, I_G may be advantageously lowered to $I_{G,steady}$ for reducing unnecessary gate drive losses. The $I_{G,steady}$ is determined by noting the DC current gain, h_{FE} , of the device

The desired $I_{G,steady}$ is determined by the peak device junction temperature T_J during operation, drain current I_D , DC current gain h_{FE} , and a 50 % safety margin to ensure operating the device in the saturation region with low on-state voltage drop by the equation:

$$I_{G,steady} \approx \frac{I_D}{h_{FE}(T, I_D)} * 1.5$$

Package Dimensions:



- NOTE**
1. CONTROLLED DIMENSION IS INCH. DIMENSION IN BRACKET IS MILLIMETER.
 2. DIMENSIONS DO NOT INCLUDE END FLASH, MOLD FLASH, MATERIAL PROTRUSIONS

| Revision History | | | |
|------------------|----------|--------------------------|------------|
| Date | Revision | Comments | Supersedes |
| 2014/08/25 | 1 | Gate Drive Theory Update | |
| 2013/09/12 | 0 | Initial release | |

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 43670 Trade Center Place Suite 155
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SPICE Model Parameters

This is a secure document. Please copy this code from the SPICE model PDF file on our website (http://www.genesicsemi.com/images/products_sic/igbt_copack/GA10SICP12-247_spice.pdf) into LTSPICE (version 4) software for simulation of the GA10SICP12-247.

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*      MODEL OF GeneSiC Semiconductor Inc.
*
*      $Revision:   1.1           $
*      $Date:      23-JUN-2014   $
*
*      GeneSiC Semiconductor Inc.
*      43670 Trade Center Place Ste. 155
*      Dulles, VA 20166
*      http://www.genesicsemi.com/index.php/sic-products/copack
*
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*
* These models are provided "AS IS, WHERE IS, AND WITH NO WARRANTY
* OF ANY KIND EITHER EXPRESSED OR IMPLIED, INCLUDING BUT NOT LIMITED
* TO ANY IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A
* PARTICULAR PURPOSE."
* Models accurate up to 2 times rated drain current.
*
* Start of GA10SICP12-247 SPICE Model
*
.SUBCKT GA10SIPC12 DRAIN GATE SOURCE
Q1 DRAIN GATE SOURCE GA10SIPC12_Q
D1 SOURCE DRAIN GA10SIPC12_D1
D2 SOURCE DRAIN GA10SIPC12_D2
.model GA10SIPC12_Q NPN
+ IS      5.00E-47          ISE      1.26E-28          EG      3.23
+ BF      100              BR       0.55              IKF     350
+ NF      1                NE       2                RB      6.97
+ RE      0.01             RC       0.1              CJC     3.5E-10
+ VJC     3                MJC     0.5              CJE     1.11E-09
+ VJE     3                MJE     0.5              XTI     3
+ XTB     -1.2             TRC1    7.00E-03          MFG     GeneSiC_Semi
.MODEL GA10SIPC12_D1 D
+ IS      4.55E-15          RS      0.0736           N       1
+ IKF     1000             EG      1.2              XTI     -2
+ TRS1    0.005434         TRS2    2.71739E-05     CJO     6.40E-10
+ VJ      0.469           M       1.508           FC      0.5
+ TT      1.00E-10
.MODEL GA10SIPC12_D2 D
+ IS      1.54E-22          RS      0.19          TRS1    -0.004
+ N       3.941           EG      3.23          IKF     19
+ XTI     0                FC      0.5          TT      0
.ENDS
* End of GA10SICP12-247 SPICE Model

```